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INTERNATIONAL STANDARD



**Semiconductor devices –
Part 5-15: Optoelectronic devices – Light emitting diodes – Test method of the
flat-band voltage based on the electroreflectance spectroscopy**

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The text of this International Standard is based on the following documents:

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| Draft | Report on voting |
| 47E/737A/CDV | 47E/764A/RVC |

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

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SEMICONDUCTOR DEVICES –

Part 5-15: Optoelectronic devices – Light emitting diodes – Test method of the flat-band voltage based on the electroreflectance spectroscopy

1 Scope

This part of IEC 60747-5 specifies the measuring methods of flat-band voltage of single GaN-based light emitting diode (LED) die or package without phosphor, based on the electroreflectance (ER) spectroscopy. White LEDs for lighting applications are out of the scope of this part of IEC 60747-5.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60747-5-6:2021, *Semiconductor devices – Part 5-6: Optoelectronic devices – Light emitting diodes*